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4	O.I.P.E.	7	PATENT DATE
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O.I.P.E.
SCANNED GNO Q.A. 7/12

PATENT DATE

APPLICATION NO. 09/994936	CONT/PRIOR F	CLASS 257	SUBCLASS	ART UNIT 2811	EXAMINER <u>HU</u>
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Sadashige Sugiura
Toshiyuki Yokoyama

Semiconductor device and testing method therefor

PTO-2040
12/89[illegible]

TERMINAL DISCLAIMER

☐ The term of this patent subsequent to _____ (date) has been disclaimed.

☐ The term of this patent shall not extend beyond the expiration date of U.S. Patent No. _____

☒ The terminal _____ months of this patent have been disclaimed.

DRAWINGS

Sheets Drwg.

Figs. Drwg.

Print Flg

(Assistant Examiner)

(Date)

(Primary Examiner)

(Date)

(Legal Instruments Examiner)

(Date _____)

CLAIMS ALLOWED

Total Claims

Print Claim for O.G.

NOTICE OF ALLOWANCE MAILED

ISSUE FEE

Amount Due

Date Paid

ISSUE BATCH NUMBER

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(FACE)